SPECIFICATION

SPEC. No. C-HighQ-a

D A T E: 2013 Sep.

То

Non-Controlled Copy

CUSTOMER'S PRODUCT NAME	TDK PRODUCT NAME
	MULTILAYER CERAMIC CHIP CAPACITORS
	C Series / Commercial Grade
	High Q

Please return this specification to TDK representatives.

If orders are placed without returned specification, please allow us to judge that specification is accepted by your side.

RECEIPT CONFIRMATION

DATE: YEAR MONTH DAY

TDK Corporation
Sales
Electronic Components
Sales & Marketing Group

TDK-EPC Corporation Engineering

Ceramic Capacitors Business Group

APPROVED Person in charge

	APPROVED	CHECKED	Person in charge

1. SCOPE

This specification is applicable to chip type multilayer ceramic capacitors with a priority over the other relevant specifications.

Production places defined in this specification shall be TDK-EPC Corporation Japan,

TDK (Suzhou) Co., Ltd, and TDK Components U.S.A. Inc.

EXPLANATORY NOTE:

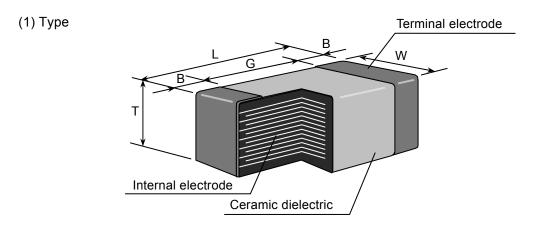
This specification warrants the quality of the ceramic chip capacitors. The chips should be evaluated or confirmed a state of mounted on your product.

If the use of the chips goes beyond the bounds of the specification, we can not afford to guarantee.

2. CODE CONSTRUCTION

(Example)

Catalog Number : (Web)	<u>C0603</u>	<u>C0G</u>	<u>1E</u>	<u>150</u>	<u>J</u>	<u>030</u>	<u>B</u>	<u>G</u>
	(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)
Item Description :	C0603	<u>C0G</u> (2)	<u>1E</u> (3)	<u>150</u> (4)	<u>J</u> (5)	<u>T</u> (9)	<u>xxxx</u> (10)	



Please refer to product list for the dimension of each product.

(2) Temperature Characteristics (Details are shown in table 1 No.6 at page 3)

(3) Rated Voltage

Symbol	Rated Voltage
1 E	DC 25 V

(4) Rated Capacitance

Stated in three digits and in units of pico farads (pF).

The first and Second digits identify the first and second significant figures of the capacitance, the third digit identifies the multiplier.

R is designated for a decimal point.

Example 150 \rightarrow 15pF

(5) Capacitance tolerance

Symbol	Tolerance	Capacitance
W	± 0.05 pF	
В	± 0.1 pF	
Е	± 0.2 pF	10pF and under
С	± 0.25 pF	
D	± 0.5 pF	
G	± 2 %	Over 10pF
J	± 5 %	Over 10pr

- (6) Thickness code (Only Catalog Number)
- (7) Package code (Only Catalog Number)
- (8) Special code (Only Catalog Number)
- (9) Packaging (Only Item Description)

Symbol	Packaging			
Т	Taping			

(10) Internal code (Only Item Description)

3. RATED CAPACITANCE AND CAPACITANCE TOLERANCE

3.1 Standard combination of rated capacitance and tolerances

Class	Temperature Characteristics	Capacitance tolerance		Rated capacitance
1	COG		W (± 0.05 pF) B (± 0.10 pF)	0.2, 0.3, 0.4, 0.5, 0.6, 0.7, 0.8, 0.9
		10pF and under	B (± 0.10 pF) C (± 0.25 pF)	1.0, 1.1, 1.2, 1.3, 1.4, 1.5, 1.6, 1.7, 1.8, 1.9, 2.0, 2.1, 2.2, 2.3, 2.4, 2.5, 2.6, 2.7, 2.8, 2.9, 3.0, 3.1, 3.2, 3.3, 3.4, 3.5, 3.6, 3.7, 3.8, 3.9, 4.0, 4.1, 4.2, 4.3, 4.4, 4.5, 4.6, 4.7, 4.8, 4.9, 5.0, 5.1, 5.6, 6.0, 6.2, 6.8, 7.0, 7.5, 8.0, 8.2, 9.0, 9.1
			E (± 0.20 pF) D (± 0.50 pF)	10.0
		Over 10pF	G (± 2 %) J (± 5 %)	E – 24 series

3.2 Capacitance Step in E series

E series	Capacitance Step											
E - 24	1.0	1.1	1.2	1.3	1.5	1.6	1.8	2.0	2.2	2.4	2.7	3.0
	3.3	3.6	3.9	4.3	4.7	5.1	5.6	6.2	6.8	7.5	8.2	9.1

4. OPERATING TEMPERATURE RANGE

T.C.	Min. operating	Max. operating	Reference
	Temperature	Temperature	Temperature
COG	-55°C	125°C	25°C

5. STORING CONDITION AND TERM

5 to 40°C at 20 to 70%RH 6 months Max.

6. INDUSTRIAL WASTE DISPOSAL

Dispose this product as industrial waste in accordance with the Industrial Waste Law.



7. PERFORMANCE

table 1

No.	Item		Perform	nance	Te	est or inspection	n method
1	External Appearance	No defects which may affect performance.			Inspect with magnifying glass (10×)		
2	Insulation Resistance	10,000ΜΩ ι	min.		Apply rate	d voltage for 60	S.
3	Voltage Proof	Withstand test voltage without insulation breakdown or other damage.			Class	Apply	voltage
					Class1	3 × rate	d voltage
					1 to 5s.	e applied for	
4	Capacitance	Within the s	specified	d tolerance.			T
					Class	Measuring frequency	Measuring voltage
					Class1	1MHz±10%	0.5 - 5 Vrms.
5	Q				See No.4	in this table for	measuring
	(Class1)	Rated Cap	acitance	Q	condition.		-
		Under 3	30pF	400+20×C min.			
		C : Rated c	ed capacitance (pF)				
6	Temperature						hall be calculated
	Characteristics of Capacitance (Class1)			ature Coefficient ppm/°C)	based on temperatu	and 85°C	
	,	COG	C0G 0 ± 30		Measuring temperature below 20°C shall be -10°C and -25°C.		
		Capacitance drift Within ± 0.2% or ±0.05pF, whichever larger.					

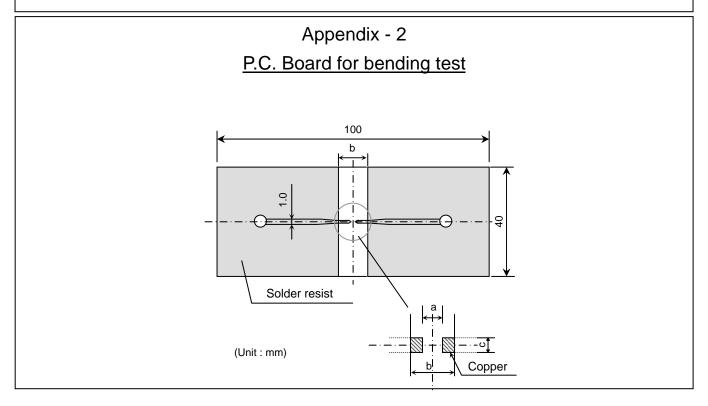
(COI	ntinued)	<u> </u>	
No.	Item	Performance	Test or inspection method
7	Robustness of Terminations	No sign of termination coming off, breakage of ceramic, or other abnormal signs.	Reflow solder the capacitors on a P.C.Board shown in Appendix 1 and apply a pushing force of 2N with 10±1s. Pushing force Capacitor P.C.Board
8	Bending	No mechanical damage.	Reflow solder the capacitors on a P.C.Board shown in Appendix 2 and bend it for 1mm.
9	Solderability	New solder to cover over 75% of termination. 25% may have pin holes or rough spots but not concentrated in one spot. Ceramic surface of A sections shall not be exposed due to melting or shifting of termination material. A section	Completely soak both terminations in solder at 235±5°C for 2±0.5s. Solder: H63A (JIS Z 3282) Flux: Isopropyl alcohol (JIS K 8839) Rosin(JIS K 5902) 25% solid solution.

No.	Ite	em	ı	Perform	nance	Test or inspection method
10	Resistance to solder heat	External appearance	No cracks are allowed and terminations shall be covered at least 60% with new solder.			Completely soak both terminations in solder at 260±5°C for 5±1s. Preheating condition
		Capacitance				Temp.: 150±10°C
			Characteris		hange from the alue before test	Time : 1 to 2min. Flux : Isopropyl alcohol (JIS K 8839)
			Class 1		2.5% or ±0.25pF, hichever larger.	Rosin (JIS K 5902) 25% solid solution.
		Q				Solder : H63A (JIS Z 3282)
		(Class1)	Rated Capa	acitance	Q	Leave the capacitors in ambient condition for 6 to 24h before measurement.
			Under 3	30pF	400+20×C min.	
			C : Rated c	apacita	ince (pF)	
		Insulation Resistance	Meet the initial spec.			
		Voltage proof	No insulation other dama		kdown or	
11	Vibration	External appearance	No mechanical damage.			Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing.
		Capacitance				
			Characteris		hange from the alue before test	Vibrate the capacitors with amplitude of 1.5mm P-P changing the frequencies from 10Hz to 55Hz and back to 10Hz in
			Class 1		2.5% or ±0.25pF, hichever larger.	about 1min. Repeat this for 2h each in 3 perpendicular directions.
		Q				
		(Class1)	Rated Capa	acitance	Q	
			Under 3	B0pF	400+20×C min.	
			C : Rated c	apacita	ince (pF)	

(CO	ntinued)						1			
No.	Ite	em	Performance			ance		Test or inspection method		
12	Temperature cycle	External Appearance Capacitance	No mechanical damage.			mage.	Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing.			
		Capacitarice	Charact	teristics		nange from the lue before test	step1	e the capacitors in th through step 4 and re cutively		
			Class 1	C0G		5% or ±0.25pF, chever larger.	Leave	Leave the capacitors in ambient condition for 6 to 24h before		
		Q					_	rement.		
		(Class1)		Capacita	nce	Q			T	
			-				Step	Temperature(°C)	Time (min.)	
			Und	ler 30pF		400+20×C min.	1	-55 ± 3	30 ± 3	
			C : Rated capacitance (pF)			nce (pF)	_ 2	Reference Temp.	2 - 5	
		Insulation	Meet the initial spec.			ec.	3	125 ± 2	30 ± 2	
		Resistance			4	Reference Temp.	2 - 5			
		Voltage proof	No insulation breakdown or other damage.			kdown or				
13	13 Moisture External Appeara (Steady		No mechanical damage.			mage.	Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing.			
	State)	Capacitance								
			Charact	teristics		nange from the lue before test	Leave at temperature 40±2°C, 90 to 95%RH for 500 +24,0h.			
				C0G	±5% whi	% or ±0.5pF, chever larger.	Leave the capacitors in ambient condition for 6 to 24h before measurement.			
		Q (Class1)		Capacita	nce	Q				
			10pF and over under 30pF		er	275+5/2×C min.				
			Und	ler 10pF		200+10×C min.				
			C : Rate	d capa	cita	nce (pF)				
		Insulation Resistance	1,000MΩ	Ω min.						

No.	It	em	Perforr	nance	Test or inspection method		
14	Moisture Resistance	External appearance			Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing.		
		Capacitance	Class COC ±7	Change from the value before test 7.5% or ±0.75pF, hichever larger.	Apply the rated voltage at temperature 40±2°C and 90 to 95%RH for 500 +24,0h. Charge/discharge current shall not exceed 50mA.		
		Q (Class1)	Rated Capacitance Q		Leave the capacitors in ambient condition for 6 to 24h before measurement.		
			Under 30pF 100+10/3×C min. C: Rated capacitance (pF)				
		Insulation Resistance	500MΩ min.				
17	Life	External appearance	No mechanical da	amage.	Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing.		
		Capacitance		Change from the value before test	Apply 2× rated voltage at 125±2°C for 1,000 +48,0h		
				3% or ±0.3pF, hichever larger.	Charge/discharge current shall not exceed 50mA.		
		Q (Class1)	Rated Capacitance	Q	Leave the capacitors in ambient condition for 6 to 24h before measurement.		
			10pF and over under 30pF	275+5/2×C min.			
			Under 10pF C: Rated capacita	200+10×C min. ance (pF)			
		Insulation Resistance	1,000MΩ min.				

Appendix - 1 P.C. Board for reliability test Solder resist Copper (Unit : mm)



Material: Glass Epoxy (As per JIS C6484 GE4)

P.C. Board thickness : Appendix-2 0.8mm

Appendix-1 1.6mm

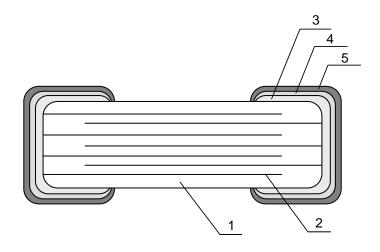
Copper (thickness 0.035mm)

Solder resist

TDK (EIA style)	Dimensions (mm)				
TDR (EIA Style)	а	b	С		
C0603 (CC0201)	0.3	0.8	0.3		



8. INSIDE STRUCTURE AND MATERIAL



No.	NAME	MATERIAL		
1	Dielectric	CaZrO ₃		
2	Electrode	Nickel (Ni)		
3		Copper (Cu)		
4	Termination	Nickel (Ni)		
5		Tin (Sn)		

9. SOLDERING CONDITION

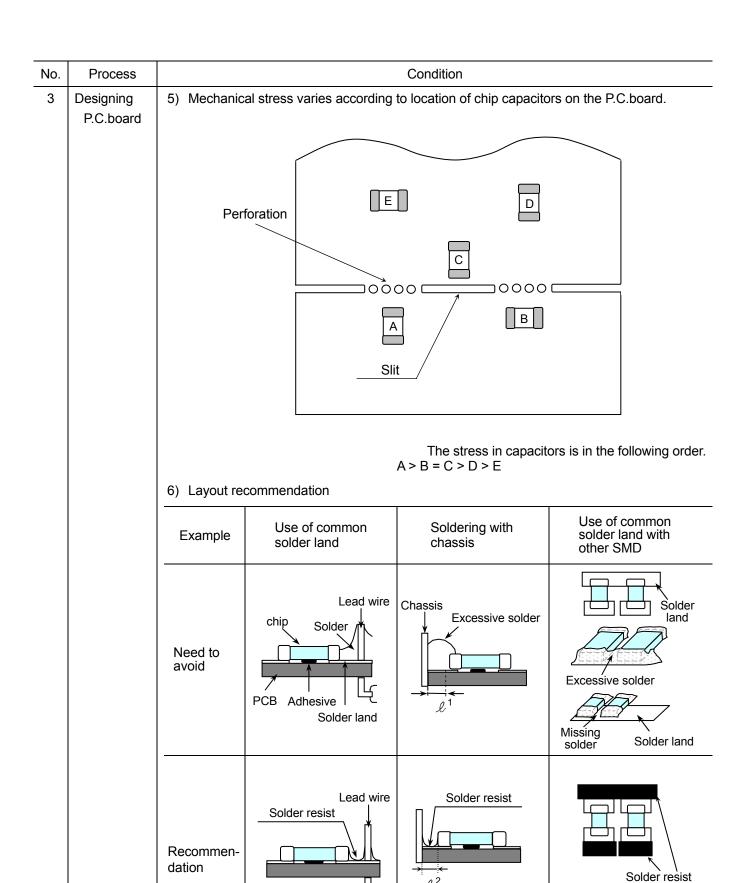
As for C0603 type, reflow soldering only.

10. Caution

	I						
No.	Process	Condition					
1	Operating Condition (Storage,	 Storage The capacitors must be stored in an ambient temperature of 5 to 40°C with a relative humidity of 20 to 70%RH. The products should be used within 6 months upon receipt. 					
	Transportation)	 The capacitors must be operated and stored in an environment free of dew condensation and these gases such as Hydrogen Sulphide, Hydrogen Sulphate, Chlorine, Ammonia and sulfur. 					
		3) Avoid storing in sun light and falling of dew.					
		4) Do not use capacitors under high humidity and high and low atmospheric pressure which may affect capacitors reliability.					
		5) Capacitors should be tested for the solderability when they are stored for long time.					
		1-2. Handling in transportation					
		In case of the transportation of the capacitors, the performance of the capacitors may be deteriorated depending on the transportation condition. (Refer to JEITA RCR-2335B 9.2 Handling in transportation)					
2	Circuit design A Caution	 2-1. Operating temperature					
		2) Surface temperature including self heating should be below maximum operating					
		temperature. (Due to dielectric loss, capacitors will heat itself when AC is applied. Especially at high frequencies around its SRF, the heat might be so extreme that it may damage itself or the product mounted on. Please design the circuit so that the maximum temperature of the capacitors including the self heating to be below the maximum allowable operating temperature. Temperature rise at capacitor surface shall be below 20°C)					
		 The electrical characteristics of the capacitors will vary depending on the temperature. The capacitors should be selected and designed in taking the temperature into consideration. Operating voltage Operating voltage across the terminals should be below the rated voltage. When AC and DC are super imposed, V_{0-P} must be below the rated voltage. 					
		AC or pulse with overshooting, V_{P-P} must be below the rated voltage.					
		When the voltage is started to apply to the circuit or it is stopped applying, the irregular voltage may be generated for a transit period because of resonance or switching. Be sure to use the capacitors within rated voltage containing these Irregular voltage.					
		Voltage (1) DC voltage (2) DC+AC voltage (3) AC voltage					
		Positional Measurement (Rated voltage) 0 V _{0-P} 0 V _{P-P} 0					
		Voltage (4) Pulse voltage (A) (5) Pulse voltage (B)					
		Positional Measurement (Rated voltage)					

No.	Process	Condition					
2	Circuit design	2) Even below the rated voltage, if repetitive high frequency AC or pulse is applied, the reliability of the capacitors may be reduced.					
	<u> </u>		rill vary depending on applied DC and AC voltages. elected and designed in taking the voltages into				
		•	s 2) are used in AC and/or pulse voltages, the mselves and generate audible sound.				
3	Designing P.C.board	capacitors. 1) The greater the amount of sand the more likely that it w	ninations has a direct effect on the reliability of the older, the higher the stress on the chip capacitors, II break. When designing a P.C.board, determine the r lands to have proper amount of solder on the				
		2) Avoid using common solder land for multiple terminations and provide individual solder land for each terminations.					
		3) Size and recommended lan	ended land dimensions.				
		C	Chip capacitors Solder land Solder resist				
		Reflow soldering	(mm)				
		Туре	C0603				
		Symbol	(CC0201)				
		А В	0.25 - 0.35 0.2 - 0.3				
		С	0.25 - 0.35				
			0.20 0.00				

No.	Process		Condition						
3	Designing P.C.board	4) Recommended	4) Recommended chip capacitors layout is as following.						
			Disadvantage against bending stress	Advantage against bending stress					
		Mounting face	Perforation or slit	Perforation or slit					
			Break P.C.board with mounted side up.	Break P.C.board with mounted side down.					
			Mount perpendicularly to perforation or slit	Mount in parallel with perforation or slit					
		Chip arrangement (Direction)	Perforation or slit	Perforation or slit					
			Closer to slit is higher stress	Away from slit is less stress					
		Distance from slit	$(\ell_1 < \ell_2)$	$\begin{array}{c c} \ell_2 \\ \hline \\ (\ell_1 < \ell_2) \end{array}$					

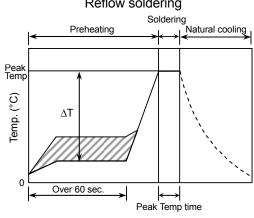


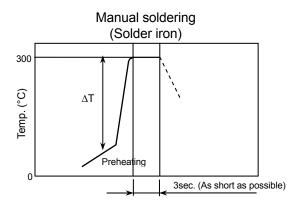


 $\ell^2 > \ell^1$

No.	Process	_	Condition				
4	Mounting	 4-1. Stress from mounting head If the mounting head is adjusted too low, it may induce excessive stress in the capacitors to result in cracking. Please take following precautions. 1) Adjust the bottom dead center of the mounting head to reach on the P.C.boa surface and not press it. 2) Adjust the mounting head pressure to be 1 to 3N of static weight. 					
		 To minimize the impact energy from mounting head, it is important to provide support from the bottom side of the P.C.board. See following examples. 					
			Not recommended	Recommended			
		Single sided mounting	Crack	Support pin			
		Double-sides mounting	Solder peeling Crack	Support pin			
		to cause crack.	ring jaw is worn out, it may give me Please control the close up dimens at preventive maintenance and repla	sion of the centering jaw and			

No.	Process	Condition
5	Soldering	5-1. Flux selection Although highly-activated flux gives better solderability, substances which increase activity may also degrade the insulation of the chip capacitors. To avoid such degradation, it is recommended following.
		It is recommended to use a mildly activated rosin flux (less than 0.1wt% chlorine). Strong flux is not recommended.
		Excessive flux must be avoided. Please provide proper amount of flux.
		3) When water-soluble flux is used, enough washing is necessary.
		5-2. Recommended soldering profile by various methods
		Reflow soldering





5-3. Recommended soldering peak temp and peak temp duration

Temp./Duration	Reflow soldering				
Solder	Peak temp(°C)	Duration(sec.)			
Sn-Pb Solder	230 max.	20 max.			
Lead Free Solder	260 max.	10 max.			

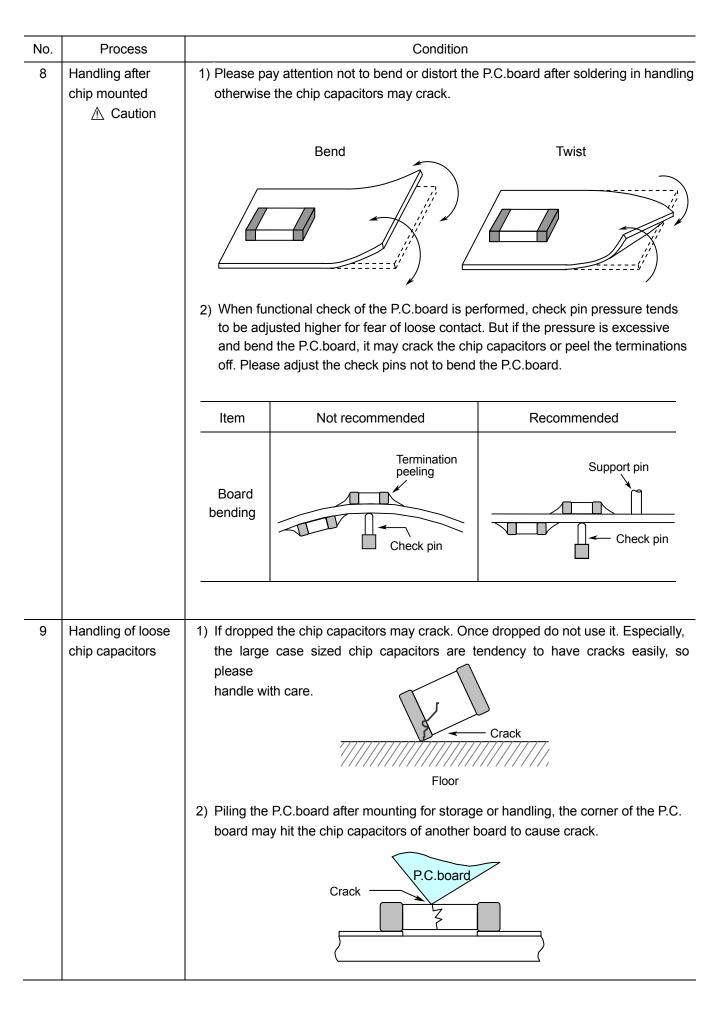
Recommended solder compositions Sn-37Pb (Sn-Pb solder) Sn-3.0Ag-0.5Cu (Lead Free Solder)



	Τ	T						
No.	Process			Cond	tion			
5	Soldering	5-4. Avoiding therm						
		Preheating con Solde		Typo	Ton	np. (°C)		
			-	Type				
		Reflow s		C0603(CC020	-	¯ ≤ 150		
		Manual s	oldering	C0603(CC020	ΔΤ ΔΤ	¯≤ 150		
		cleaning, the te	using air emperatur der solder wi e changes	is recommende re difference (ΔT sill induce higher and it may result from the P.C.bo) must be less r tensile forcult in chip crac	s than 100°C. ce in chip car	pacitors when ent solder may force in	
		Adequate				imum amount mum amount		
		Insufficient solder				Low robustnes cause contact chip capacitors the P.C.board.	failure or s come off	
		5-6. Solder repair by solder iron 1) Selection of the soldering iron tip Tip temperature of solder iron varies by its type, P.C.board material and solder land size. The higher the tip temperature, the quicker the operation. However, heat shock may cause a crack in the chip capacitors. Please make sure the tip temp. before soldering and keep the peak temp and time in accordance with following recommended condition. (Please preheat the chip capacitors with the condition in 5-4 to avoid the thermal shock.) Recommended solder iron condition (Sn-Pb Solder and Lead Free Solder) Temp. (°C) Duration (sec.) Wattage (W) Shape (mm) 300 max. 3 max. 20 max. Ø 3.0 max.						

No.	Process	Condition
5	Soldering	 2) Direct contact of the soldering iron with ceramic dielectric of chip capacitors may cause crack. Do not touch the ceramic dielectric and the terminations by solder iron. 5-7. Sn-Zn solder 5n-Zn solder affects product reliability. Please contact TDK in advance when utilize Sn-Zn solder. 5-8. Countermeasure for tombstone The misalignment between the mounted positions of the capacitors and the land patterns should be minimized. The tombstone phenomenon may occur especially the capacitors are mounted (in longitudinal direction) in the same direction of the reflow soldering. (Refer to JEITA RCR-2335B Annex 1 (Informative) Recommendations to prevent the tombstone phenomenon)
6	Cleaning	 If an unsuitable cleaning fluid is used, flux residue or some foreign articles may stick to chip capacitors surface to deteriorate especially the insulation resistance. If cleaning condition is not suitable, it may damage the chip capacitors. Insufficient washing Terminal electrodes may corrode by Halogen in the flux. Halogen in the flux may adhere on the surface of capacitors, and lower the insulation resistance. Water soluble flux has higher tendency to have above mentioned problems (1) and (2). Excessive washing When ultrasonic cleaning is used, excessively high ultrasonic energy output can affect the connection between the ceramic chip capacitor's body and the terminal electrode. To avoid this, following is the recommended condition.
7	Coating and molding of the P.C.board	 When the P.C.board is coated, please verify the quality influence on the product. Please verify carefully that there is no harmful decomposing or reaction gas emission during curing which may damage the chip capacitors. Please verify the curing temperature.





No.	Process	Condition
10	Capacitance aging	The capacitors (Class 2) have aging in the capacitance. They may not be used in precision time constant circuit. In case of the time constant circuit, the evaluation should be done well.
11	Estimated life and estimated failure rate of capacitors	As per the estimated life and the estimated failure rate depend on the temperature and the voltage. This can be calculated by the equation described in JEITA RCR-2335B Annex 6 (Informative) Calculation of the estimated lifetime and the estimated failure rate (Voltage acceleration coefficient: 3 multiplication rule, Temperature acceleration coefficient: 10°C rule) The failure rate can be decreased by reducing the temperature and the voltage but they will not be guaranteed.
12	Others A Caution	The products listed on this specification sheet are intended for use in general electronic equipment (AV equipment, telecommunications equipment, home appliances, amusement equipment, computer equipment, personal equipment, office equipment, measurement equipment, industrial robots) under a normal operation and use condition.
		The products are not designed or warranted to meet the requirements of the applications listed below, whose performance and/or quality require a more stringent level of safety or reliability, or whose failure, malfunction or trouble could cause serious damage to society, person or property. Please understand that we are not responsible for any damage or liability caused by use of the products in any of the applications below or for any other use exceeding the range or conditions set forth in this specification sheet. If you intend to use the products in the applications listed below or if you have special requirements exceeding the range or conditions set forth in this specification, please contact us.
		 (1) Aerospace/Aviation equipment (2) Transportation equipment (cars, electric trains, ships, etc.) (3) Medical equipment (4) Power-generation control equipment (5) Atomic energy-related equipment (6) Seabed equipment (7) Transportation control equipment (8) Public information-processing equipment (9) Military equipment (10) Electric heating apparatus, burning equipment (11) Disaster prevention/crime prevention equipment (12) Safety equipment (13) Other applications that are not considered general-purpose applications When designing your equipment even for general-purpose applications, you are
		When designing your equipment even for general-purpose applications, you are kindly requested to take into consideration securing protection circuit/device or providing backup circuits in your equipment.



11. Packaging label

Packaging shall be done to protect the components from the damage during transportation and storing, and a label which has the following information shall be attached.

- 1) Inspection No.
- 2) TDK P/N
- 3) Customer's P/N
- 4) Quantity

*Composition of Inspection No.

Example
$$\underline{M}$$
 $\underline{2}$ \underline{A} - \underline{OO} - \underline{OOO} (a) (b) (c) (d) (e)

- a) Line code
- b) Last digit of the year
- c) Month and A for January and B for February and so on. (Skip I)
- d) Inspection Date of the month.
- e) Serial No. of the day

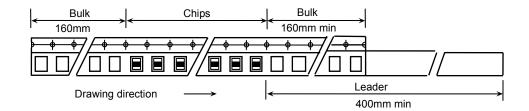
12. TAPE PACKAGING SPECIFICATION

1. CONSTRUCTION AND DIMENSION OF TAPING

1-1. Dimensions of carrier tape

Dimensions of paper tape shall be according to Appendix 3.

1-2. Bulk part and leader of taping

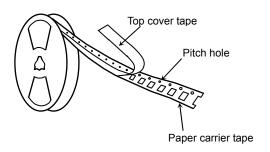


1-3. Dimensions of reel

Dimensions of Ø178 reel shall be according to Appendix 4.

Dimensions of Ø330 reel shall be according to Appendix 5.

1-4. Structure of taping



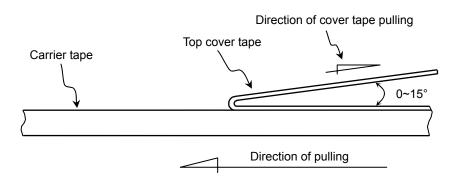
2. CHIP QUANTITY

Type	Thickness	Taping	Chip quantity(pcs.)		
туре	of chip	Material	Ф178mm reel	Ф330mm reel	
C0603	0.30 mm	paper	15,000	50,000	



3. PERFORMANCE SPECIFICATIONS

3-1. Fixing peeling strength (top tape) 0.05-0.7N. (See the following figure.)

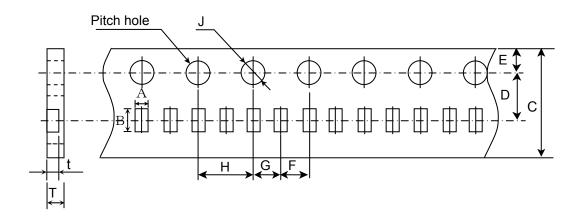


- 3-2. Carrier tape shall be flexible enough to be wound around a minimum radius of 30mm with components in tape.
- 3-3. The missing of components shall be less than 0.1%
- 3-4. Components shall not stick to fixing tape.
- 3-5. The fixing tapes shall not protrude beyond the edges of the carrier tape not shall cover the sprocket holes.



Appendix 3

Paper Tape

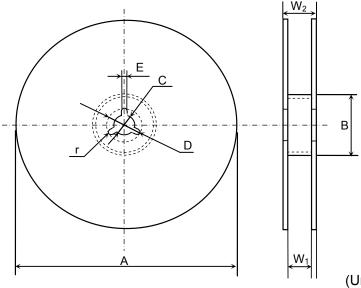


						(Unit : mm)
Symbol Type	А	В	С	D	E	F
C0603 (CC0201)	(0.38)	(0.68)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	2.00 ± 0.05
Symbol Type	G	Н	J	t	Т	
C0603 (CC0201)	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 ^{+0.10} ₀	0.35 ± 0.02	0.40 min.	

^{*} The values in the parentheses () are for reference.

Appendix 4

(Material : Polystyrene)

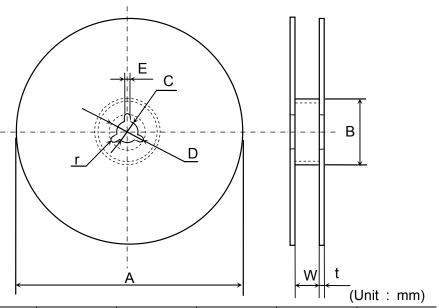


	Γ			1	<u> </u>	Unit: mm)
Symbol	Α	В	С	D	Е	W_1
Dimension	Ø178 ± 2.0	Ø60 ± 2.0	Ø13 ± 0.5	Ø21 ± 0.8	2.0 ± 0.5	9.0 ± 0.3

Symbol	W_2	r
Dimension	13.0 ± 1.4	1.0

Appendix 5

(Material : Polystyrene)



Symbol	А	В	С	D	E	W
Dimension	Ø382 max. (Nominal Ø 330)	Ø 50 min.	Ø 13 ± 0.5	Ø 21 ± 0.8	2.0 ± 0.5	10.0 ± 1.5

Symbol	t	r
Dimension	2.0 ± 0.5	1.0

